

Notice of References Cited	Application/Control No. 10/580,207		Applicant(s)/Patent Under Reexamination TSUSHIMA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,513,172 A	04-1996	Shikama et al.	370/428
*	B	US-5,751,954 A	05-1998	Saito, Shuichi	709/245
*	C	US-5,802,316 A	09-1998	Ito et al.	709/249
*	D	US-6,104,713 A	08-2000	Nagami et al.	370/392
*	E	US-6,397,260 B1	05-2002	Wils et al.	709/238
*	F	US-6,389,023 B1	05-2002	Matsuzawa et al.	370/395.31
*	G	US-2002/0181459 A1	12-2002	Ohta et al.	370/389
*	H	US-2003/0231628 A1	12-2003	Harada et al.	370/389
*	I	US-2004/0081153 A1	04-2004	Mayer et al.	370/392
*	J	US-2004/0109452 A1	06-2004	Takihiro et al.	370/392
*	K	US-6,947,415 B1	09-2005	Nagaraj, Alwarkurichi Padmana	370/389
*	L	US-2008/0049619 A1	02-2008	Twiss, Adam	370/236
*	M	US-2009/0016345 A1	01-2009	Tsuchiya et al.	370/390

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	X					

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